Study of hygroscopic expansion of anode readout boards of gaseous detectors based on FR4

J. Bortfeldt, F. Dubinin, P. lengo, J. Samarati

Introduction

Readout boards of modern gaseous detectors required to be very precise:

▶ Required accuracy $\leq 100 \mu m$

FR4 been a standard base material of the PCBs is hygroscopic

- FR4 swells under humidity exposure
- For large-size boards as ones used in Micromegas the hygroscopic expansion can be crucial

In the work the water absorption process by specific FR4 material is experimentally studied:

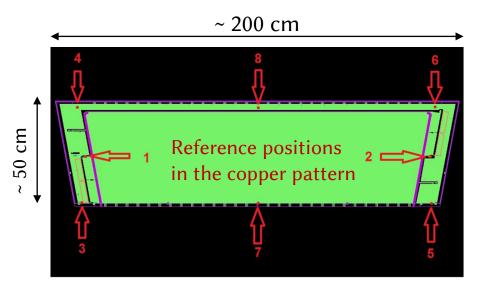
Specifics of diffusion in FR4 are discussed

Methods for measurements of expansion are considered

Measurements with 2 FR4 samples are presented and discussed

Long-term measurements with ATLAS pre-series boards

- The boards brought into the laboratory from outside
- stored for ~1 month
- without T & RH control
- ➤ with T & RH monitoring



Long-term measurements with ATLAS pre-series boards

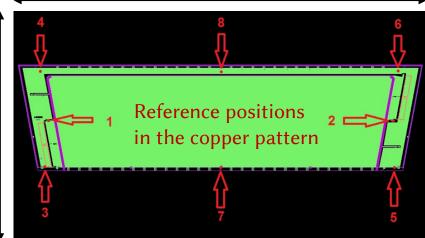
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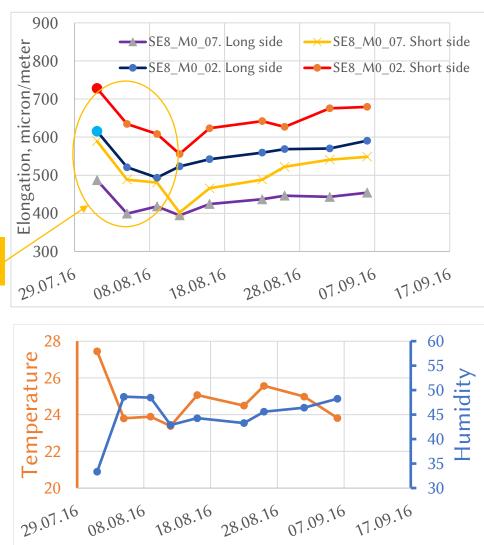
Precise direction

- ➢ without T & RH control
- with T & RH monitoring Results:
- Elongation up to 700 µm/m from nominal values

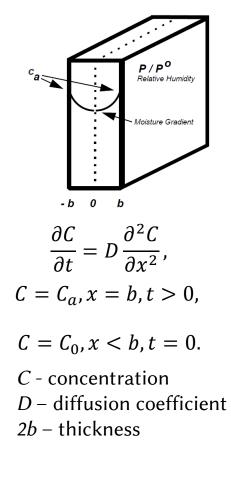
Conditioning in the laboratory atmosphere

Non-precise direction. Strips are parallel to the arrow.



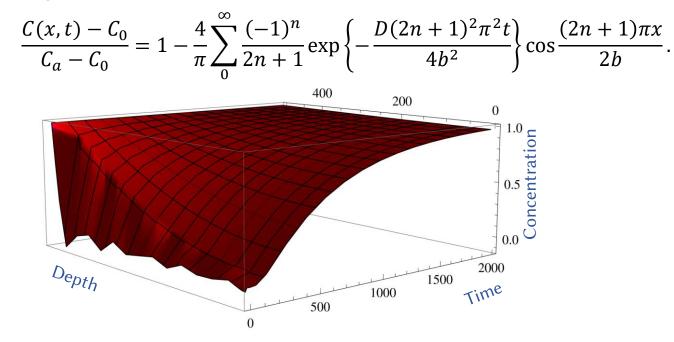


Mathematics of diffusion



Mathematics of diffusion

The corresponding solution of the Cauchy problem for diffusion in a plane sheet (1D case) is



$$\frac{\partial C}{\partial t} = D \frac{\partial^2 C}{\partial x^2},$$

$$C = C_a, x = b, t > 0,$$

$$C = C_0, x < b, t = 0.$$

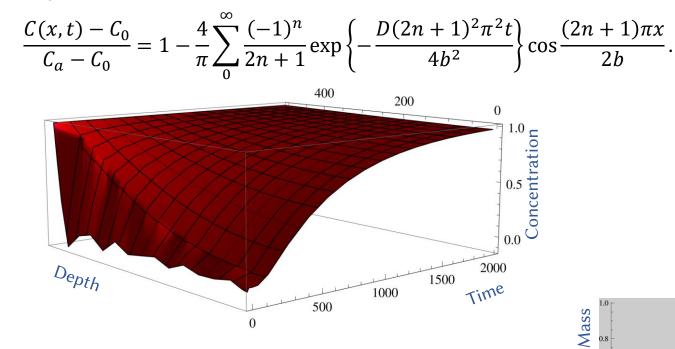
$$C - \text{ concentration}$$

$$D - \text{ diffusion coefficient}$$

$$b - \text{ thickness}$$

Mathematics of diffusion*

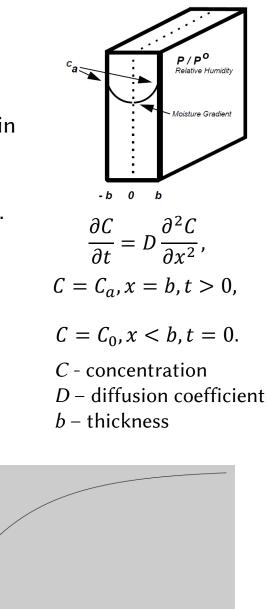
The corresponding solution of the Cauchy problem for diffusion in a plane sheet (1D case) is



Integrating along the depth direction one gets the function corresponding to the water mass uptake:

$$\frac{M(t)}{M_{\infty}} = 1 - \frac{8}{\pi^2} \sum_{n=0}^{\infty} \frac{1}{(2n+1)^2} \exp\left[-\frac{D(2n+1)^2 \pi^2}{4b^2}t\right].$$

*More information one can find in [1].



500

1000

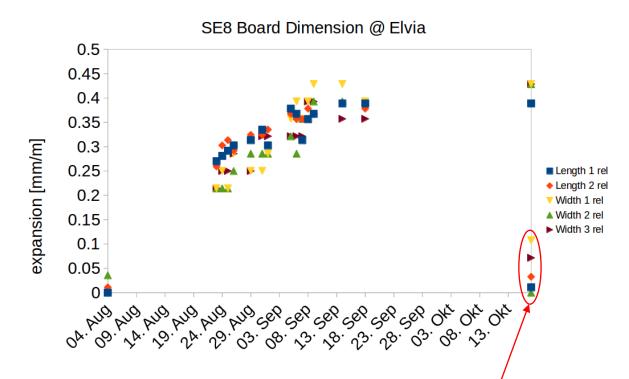
Time

1500

2000

7

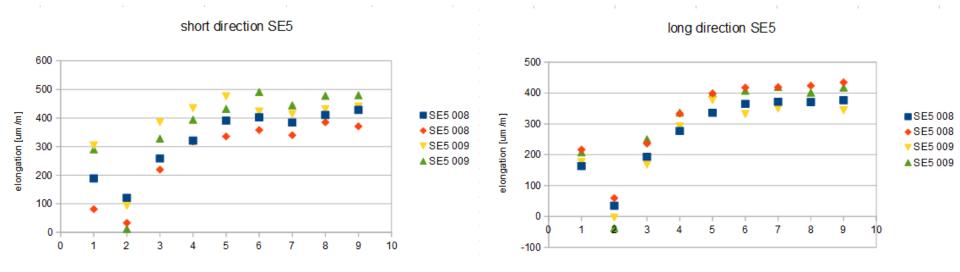
Long-term measurements by ELVIA at 50% RH



Saturation reached at 400 μm/m in ~ 1 month
 Consequential heating up to 130°C resulting in recovering of the board

Solution adopted by ATLAS is to rescale the mask of the initial copper image \gg Applied scaling factor for ELVIA boards is ~ 400 μ m/m

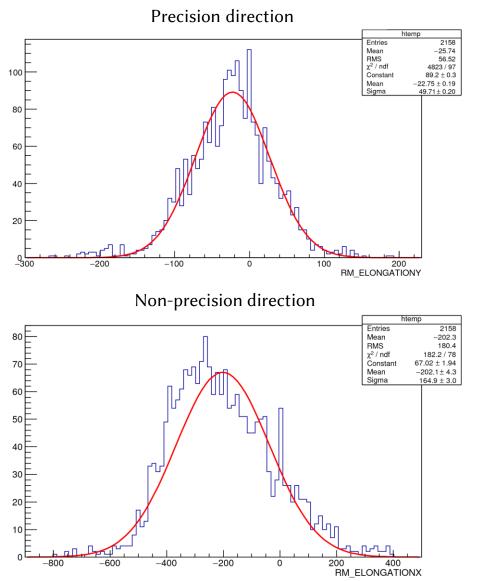
Long-term measurements by ELTOS at 50% RH



Saturation along strips was reached at ~390 µm/m
 Across strips – at ~430 µm/m

> Applied scaling factor for ELTOS boards is ~ 430 μ m/m in both directions

Statistics on series anode PCBs



The measurements done during QA/QC procedure at CERN using the specific optical tool

Specified tolerance ≻Precise direction: ±100 μm ≻Non-precise direction: ±500 μm

Precise direction:

Average elongation: -25.74 μm
 Uniformity (sigma): 56.52 μm

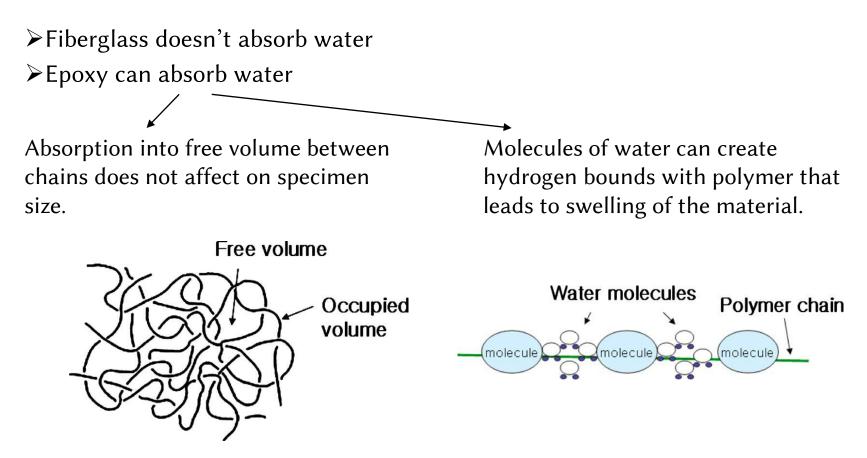
Non-precise direction: ≻Average elongation : -202.3 µm ≻Uniformity: 180.4 µm

Rescaling worked well!

Principles of water absorption in FR4

FR4 is a composite material: fiberglass grid layers filled with epoxy, pressed and cured.

Epoxy consists of polymer chains with free spaces between them.



Influence of copper layers [2]

Copper layers act as a barrier to water

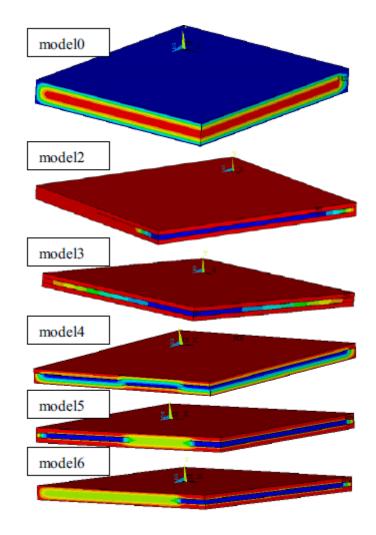
Experimental results confirmed by modeling

Here on the pictures:

► Red – 0% RH

≻Blue – 100% RH

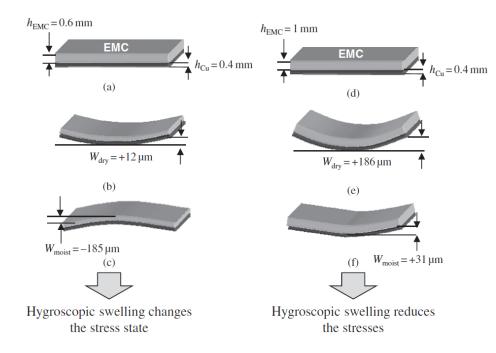
model3	model6
model4	model2
model0	model5



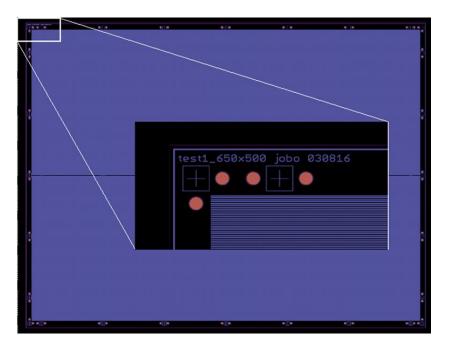
Methods for swelling estimation

- ≻Using micrometer [3]
- Moiré interferometry [4]
 - submicron accuracy
- ≻Thermomechanical analysis [5]
 - only desorption process can be studied
- ➤Warpage Measurement of Bimaterial sample [5]
 - can be compared with modeling of internal stresses in a specimen

The methods can be applied only to small-size specimens.



Experimental technique



Two samples:

- ≻650x500x0.5 mm
- Fiberglass FR4 EM-370DDM
- Copper layers of 18 μm thick
- ➤ 1024 copper strips on face side
- 1st sample has no copper on back side
- $> 2^{nd}$ sample has entire layer of copper on back side
- Standard test by supplier showed less than 0.1% change of the mass of the dry sample
- We didn't find any reference study on the expansion of this material

Experimental technique

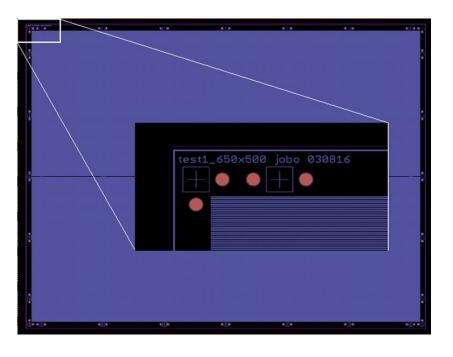


Table 1. Initial dimensions of the samples.							
	Along strips, mm			Across strips, mm			
Sample	Тор	Middle	Bottom	Left	Middle	Right	
1	638.068	638.062	638.071	484.079	484.075	484.062	
2	638.082	638.036	638.034	484.032	484.022	484.020	

Two samples:

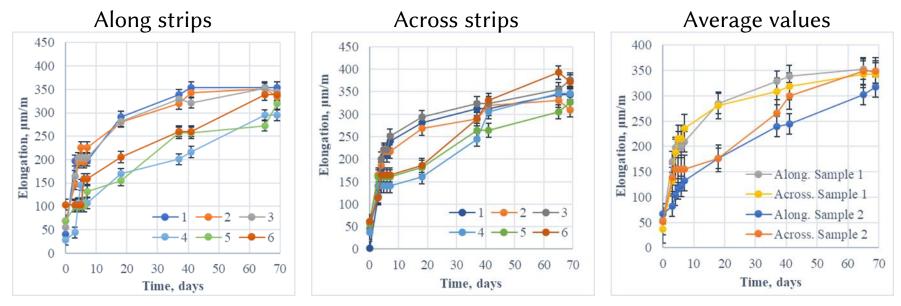
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- Standard test by supplier showed less than 0.1% change of the mass of the dry sample
- We didn't find any reference study on the expansion of this material
- Preconditioned at 130°C for 24h
 Moisture conditioning done using the climatic chamber at CERN
- Measurements done using precise glass ruler outside the chamber
- $\rightarrow \sigma_{inst} = 5 \ \mu m$
- Elongation expressed as

$$\succ L = (l_t - l_0)/l_0 \cdot 10^6 \, \mu m/m$$

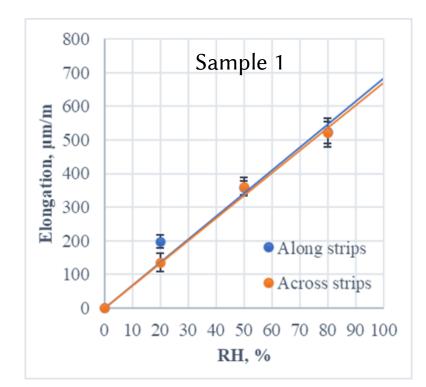
Elongation at 50% RH and 21°C

- The samples (almost) reached saturation
- Measurements at different positions are consistent
- Values for the sample 2 are less consistent

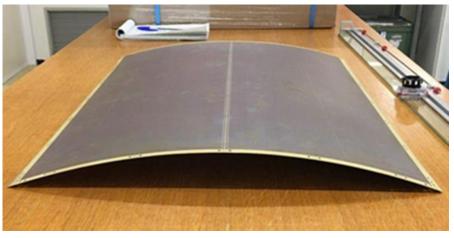
- Rate is different for the two samples but not for different directions
- Saturation value is approximately the **same** for both samples
- ► Reached at ~350 μ m/m



Coefficient of linear expansion



Sample 2

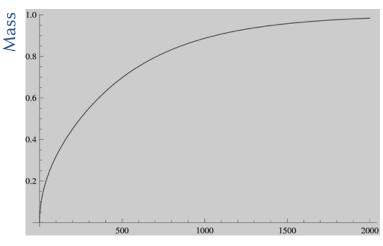


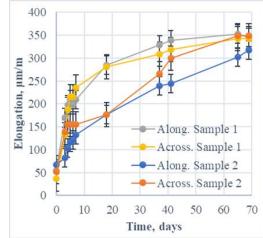
The measurements done only for sample 1

$$\begin{split} & \triangleright \beta_{||} = (7.1 \pm 0.3) \ \mu m/m / \% \\ & \triangleright \beta_{\perp} = (6.9 \pm 0.4) \ \mu m/m / \% \\ & <\beta> = (7.0 \pm 0.2) \ \mu m/m / \% \end{split}$$

- Large board bended affected by moisture
- Shape recovered after drying the board

Characterization of expansion rate. Partial diffusion coefficient.





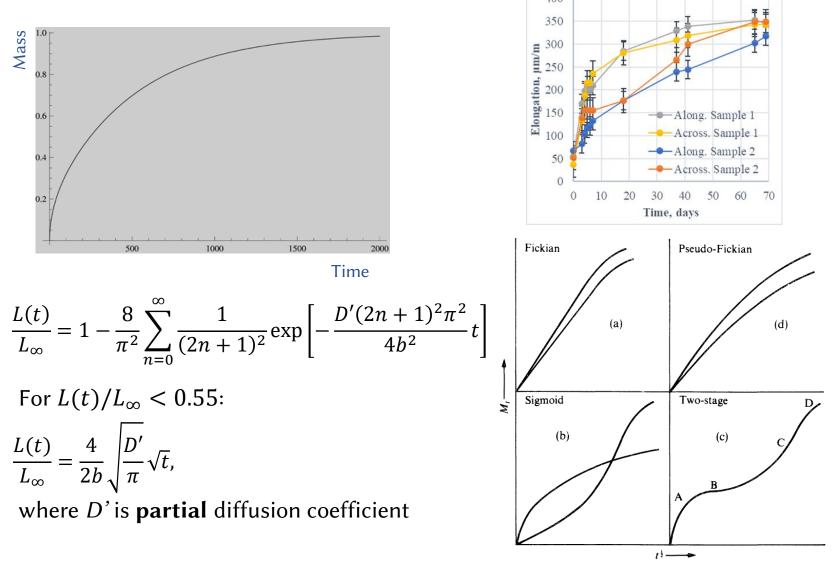
Time

$$\frac{L(t)}{L_{\infty}} = 1 - \frac{8}{\pi^2} \sum_{n=0}^{\infty} \frac{1}{(2n+1)^2} \exp\left[-\frac{D'(2n+1)^2 \pi^2}{4b^2}t\right]$$

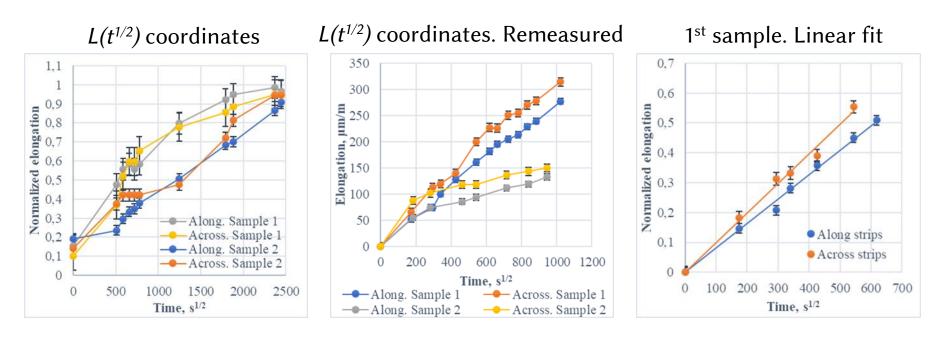
For $L(t)/L_{\infty} < 0.55$: $\frac{L(t)}{L_{\infty}} = \frac{4}{2b} \sqrt{\frac{D'}{\pi}} \sqrt{t},$

where *D*' is **partial** diffusion coefficient

Characterization of expansion rate. Partial diffusion coefficient.



Partial diffusion coefficient



Coordinates Difference between the samples is obvious in $L(t^{1/2})$ coordinates During the first two days the samples expand simultaneously

At 21°C and 50% RH the partial diffusion coefficients for the sample w/o full copper layer measured to be

 $D'_{\parallel} = (3.4 \pm 0.2) \times 10^{-2} \,\mu m^2/s$ $D'_{\perp} = (4.7 \pm 0.5) \times 10^{-2} \,\mu m^2/s$

Conclusion

➤ Rates of elongation of both samples differ from each other as well as in directions along and across strips of each sample.

• This difference is accounted for the different copper pattern of the samples.

> The equilibrium elongation in both directions of both samples is consistent within the measurement errors.

- > The linear swelling coefficient for the sample w/o full copper layer is
 - $\beta = (7.0 \pm 0.2) \ \mu m/m/\%.$

> The swelling of the sample w/o full copper layer is described by the solution of the Fick's equation for an infinite sheet. Partial diffusion coefficients at $21^{\circ}C/50\%$ RH along and across the copper strips is

- $D'_{\parallel} = (3.4 \pm 0.2) \times 10^{-2} \,\mu m^2/s$
- $D'_{\perp} = (4.7 \pm 0.5) \times 10^{-2} \,\mu m^2/s$

 \blacktriangleright For the sample with copper layer on back side, the elongation curves cannot be described by the solution of the Fick's equation.

Acknowledgments

We would like to express gratitude to Rui De Oliveira and CERN PCB Production Workshop for the production of the samples and the valuable discussions, and the CERN Bond Lab for the usage of the climatic chamber and the working space in the clean room of the lab.

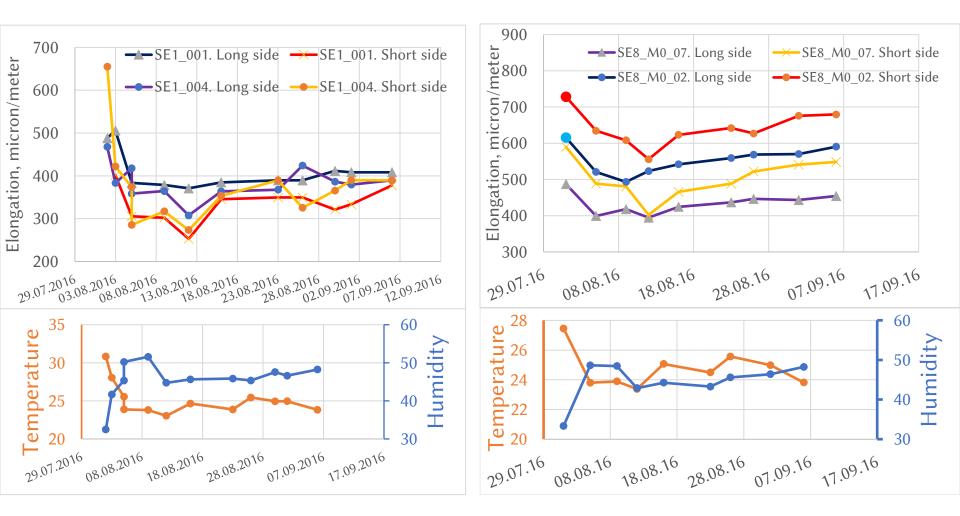
References

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- 3. Adamson, M.J., Thermal expansion and swelling of cured epoxy resin used in graphite/epoxy composite materials, J Mater Sci 15, 1736–1745 (1980).
- 4. Yoon, J., Kim, I. and Lee, S., *Measurement and Characterization of the Moisture-Induced Properties of ACF Package, ASME. J. Electron. Packag.* 2009, 131(2): 021012.
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Long-term measurements with pre-series boards

boards kept in the room with neither t nor RH control



Dimensional Inspection

absolute width & length

six rasmasks per board

boards too large: 0.4mm/m \rightarrow large problems with precision, edges & holes

distortions

- registration of strip position in center + rasmasks
- > nine contact CCDs on granite table
- surveyors resting on pairs of precision spheres O(30µm), glued onto table
- fast measurement and analysis with custom GUI with direct interface to QC form (Pavia, Tokyo)
- flexible configuration

